Se	earch	Notes	\$



Application/Control No.	Applicant(s)/Patent under Reexamination
10/612,097	ECKHART ET AL.
Examiner	Art Unit
J. Derek Rutten	2192

SEARCHED				
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	9/13/2007	JDR
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